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## SUPPLEMENTARY INFORMATION

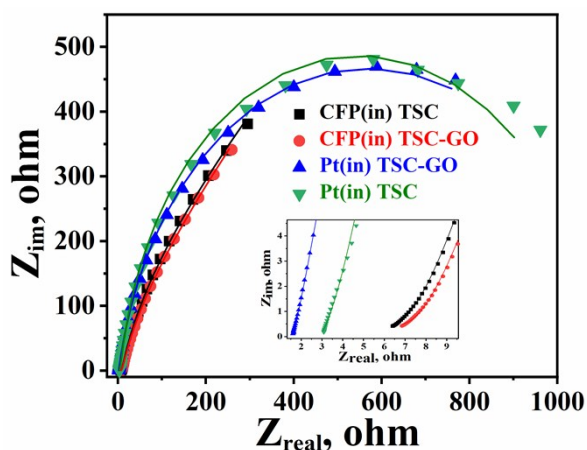
### 2 Electrochemical Reduction of CO<sub>2</sub> to Ethylene on Cu/Cu<sub>x</sub>O-GO composites in Aqueous 3 Solution

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7 The role of GO in the electrolyte on the synthesis of composites bath was accounted for  
8 by taking EIS of the electrolyte bath with and without GO and with Pt or CFP as working  
9 electrode.



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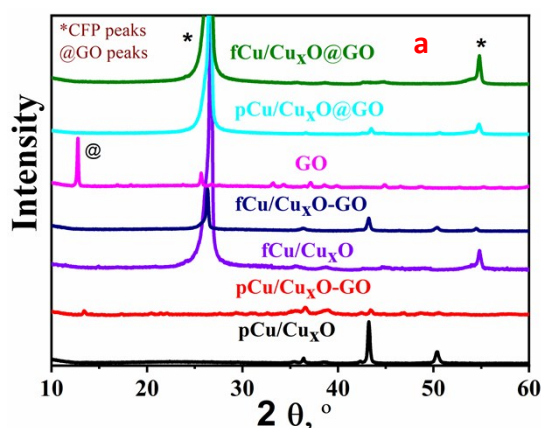
11 *Figure SI-1: EIS of Pt and CFP in a 0.2 M TSC solution with or without GO. Inset showing the*  
12 *change in the solution resistance. The graphs were fitted with  $[R_s([RQ]Q)W]$  circuit.*

### 13 Material Characterization:

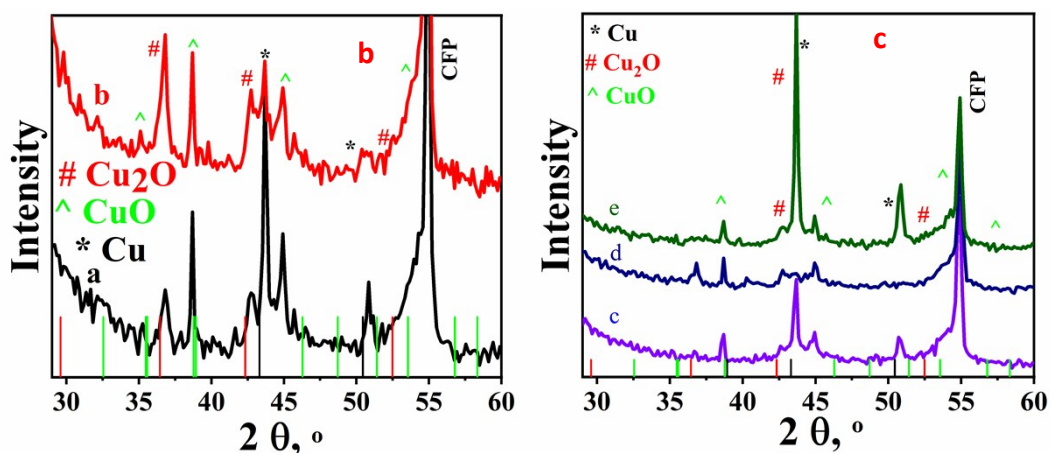
14 The XRD patterns of pCu/Cu<sub>x</sub>O and pCu/Cu<sub>x</sub>O-GO (figure SI-2 (b)) depicts major  
15 diffraction peaks positioned at 43° and 51° corresponding to (111) and (200) planes of *fcc*  
16 structure of metallic copper (JCPDS No. 85-1326). Few minor peaks located at 36° and 42°  
17 related to diffraction from (111) and (200) planes of *fcc* Cu<sub>2</sub>O (JCPDS No. 05-0667) can also  
18 be noticed in these XRD patterns. Interestingly, upon addition of GO in case of pCu/Cu<sub>x</sub>O-GO,  
19 comparatively more oxide phase of copper was observed than pCu/Cu<sub>x</sub>O was noticed. The  
20 XRD pattern of pCu/Cu<sub>x</sub>O-GO depicts diffraction peaks positioned at 36° and 42° related to  
21 reflections from (111) and (200) planes of Cu<sub>2</sub>O phase. Besides, few peaks located at 35°, 38°,  
22 and 49° corresponding to diffraction from (11 $\bar{1}$ ), (111), and (200) planes of *monoclinic* CuO  
23 (JCPDS file No. 48-1548), few significant peaks from metallic Cu are also noted. Thus, the  
24 presence of GO in the electrophoretic setup seems to favour the oxide phase than the metallic  
25 Cu in pCu/Cu<sub>x</sub>O-GO which is a manifestation of oxygen group transfer from GO to copper  
26 occurring when copper interacts with the available -C-O bonds of GO. This oxide phase  
27 preference can be realised from XRD peak ratio of Cu<sub>x</sub>O/Cu as given in table SI-1; composites  
28 have more intense peaks for Cu<sub>x</sub>O than Cu.

29 The XRD patterns for fCu/Cu<sub>x</sub>O, fCu/Cu<sub>x</sub>O-GO, and fCu/Cu<sub>x</sub>O@GO (figure SI-2 (c))  
30 show the combination of different copper phases and again addition of GO leads to more oxide  
31 phases as inferred from pCu/Cu<sub>x</sub>O and pCu/Cu<sub>x</sub>O-GO (table SI-1). However, the change in

32 cathode material from Pt to CFP does not appreciably change the crystallographic phases  
 33 obtained through electrochemical deposition though morphological changes are observed from  
 34 FESEM images. These observations from the XRD project the influence of GO on phase  
 35 preference of copper/copper oxide nano-structures which we attribute to the interaction  
 36 between GO and copper, where the former one is reduced and the later adheres to GO as oxide.  
 37 This variation in crystalline phases would directly influence the electrocatalytic activity of  
 38 these copper-based electro-catalyst materials.  
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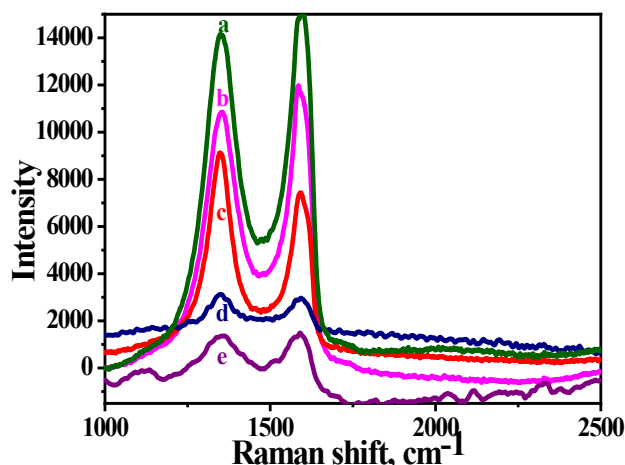


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42 **SI-2.** XRD patterns of Cu/Cu<sub>x</sub>O and its composites with GO. (a) overlay of Cu/Cu<sub>x</sub>O-GO  
 43 composites with intense CFP peaks; (b) (a trace) pCu/Cu<sub>x</sub>O, and (b trace) pCu/Cu<sub>x</sub>O-GO; (c);  
 44 (c trace) fCu/Cu<sub>x</sub>O, (d trace) fCu/Cu<sub>x</sub>O-GO, (e) fCu/Cu<sub>x</sub>O@GO. The bar diagram in both the  
 45 panels corresponds to JCPDS data from file numbers 48-1548 of fcc-CuO (green bars), 05-  
 46 0667 of fcc-Cu<sub>2</sub>O (red bars), and 85-1326 of fcc-metallic Cu (black bars).

47 Further to support the formation of a composite and deduce an idea about the extent of  
 48 reduction of GO into rGO (reduced graphene oxide because of composite formation) (which  
 49 also reflects the extent of defects in GO sheets manifested in I<sub>D</sub>/I<sub>G</sub> ratio) hence a presentation  
 50 of extent of metal – GO interactions. Raman spectra were recorded for all the composite  
 51 samples containing GO, as shown in the SI-3. The characteristic peaks were observed for  
 52 pristine GO sample i.e. peaks positioned at 1350 cm<sup>-1</sup> corresponding to D band (related to  
 53 degree of order/disorder due to a breathing k-point phonon of A<sub>1g</sub> symmetry) and at 1590 cm<sup>-1</sup>  
 54 corresponding to G band (related to the E<sub>2g</sub> phonon of sp<sup>2</sup> hybrid carbon atoms, which is an

55 indicator of the stacking structure) [1]. All the composite samples demonstrate an enhancement  
 56 in intensity of D band and lowering in intensity of G band as compared to pristine GO  
 57 indicating the formation of a composite between Cu/Cu<sub>x</sub>O and GO. Furthermore, ratio of  
 58 intensities of D band to that of G band (i.e. I<sub>D</sub>/I<sub>G</sub> ratios) estimated from the Raman spectra (table  
 59 SI-1) suggest a trend which is in accordance with the observations made from XRD and EDX  
 60 analysis. Particularly, electrodeposited sample using Pt cathode i.e. pCu/Cu<sub>x</sub>O-GO shows  
 61 highest I<sub>D</sub>/I<sub>G</sub> intensity ratio of 1.23, followed by fCu/Cu<sub>x</sub>O@GO with I<sub>D</sub>/I<sub>G</sub> = 1.19, fCu/Cu<sub>x</sub>O-  
 62 GO with I<sub>D</sub>/I<sub>G</sub> = 1.05, pCu/Cu<sub>x</sub>O@GO with I<sub>D</sub>/I<sub>G</sub> = 0.92, and pristine GO showing the lowest  
 63 I<sub>D</sub>/I<sub>G</sub> ratio of 0.88. Pertinent to mention that higher I<sub>D</sub>/I<sub>G</sub> ratio reflects a greater extent of charge  
 64 shared between metal and the GO support.



65

66 **Figure SI-3.** Raman spectra of the composites with D and G bands at 1350 cm<sup>-1</sup> and 1590  
 67 cm<sup>-1</sup>, (a) fCu/Cu<sub>x</sub>O@GO, (b) GO, (c) pCu/Cu<sub>x</sub>O-GO, (d) fCu/Cu<sub>x</sub>O-GO and (e)  
 68 pCu/Cu<sub>x</sub>O@GO.

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70 **Table SI-1: Summary of the physico-chemical parameters obtained from XRD and Raman**  
 71 **spectral analysis.**

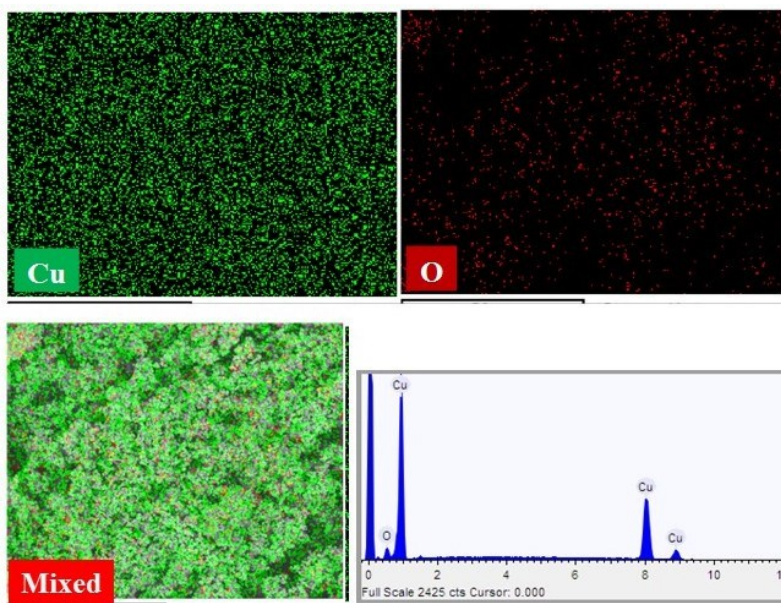
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Samples	GO support	Cathode (synthesis)	I <sub>D</sub> /I <sub>G</sub> ratio	Cu <sub>x</sub> O/Cu before electrolysis	Cu <sub>x</sub> O/Cu after electrolysis
pCu/Cu <sub>x</sub> O	--	Pt	--	0.890	0.593
pCu/Cu <sub>x</sub> O-GO	GO	Pt	1.31	2.60	0.82
fCu/Cu <sub>x</sub> O	--	CFP	--	1.17	0.977
fCu/Cu <sub>x</sub> O-GO	GO	CFP	1.01	2.02	1.263
fCu/Cu <sub>x</sub> O@GO	GO	CFP	0.93	0.851	0.536
pCu/Cu <sub>x</sub> O@GO	GO	--	--	--	--
GO	GO	--	0.92	--	--

73 **SI-4: Elemental mapping of different samples.**

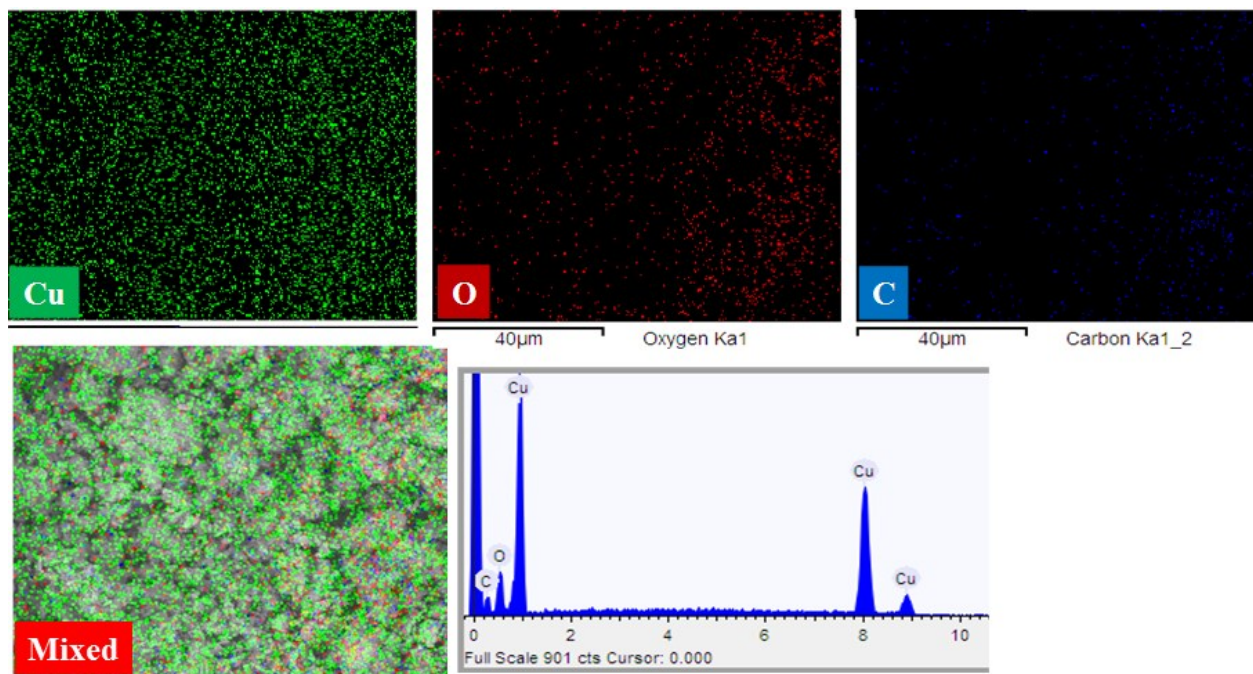
74 All samples were found devoid of any impurity, and distribution of constituent elements was  
75 homogenous.

76 **(a) pCu/Cu<sub>x</sub>O**



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78 **(b) pCu/Cu<sub>x</sub>O-GO**



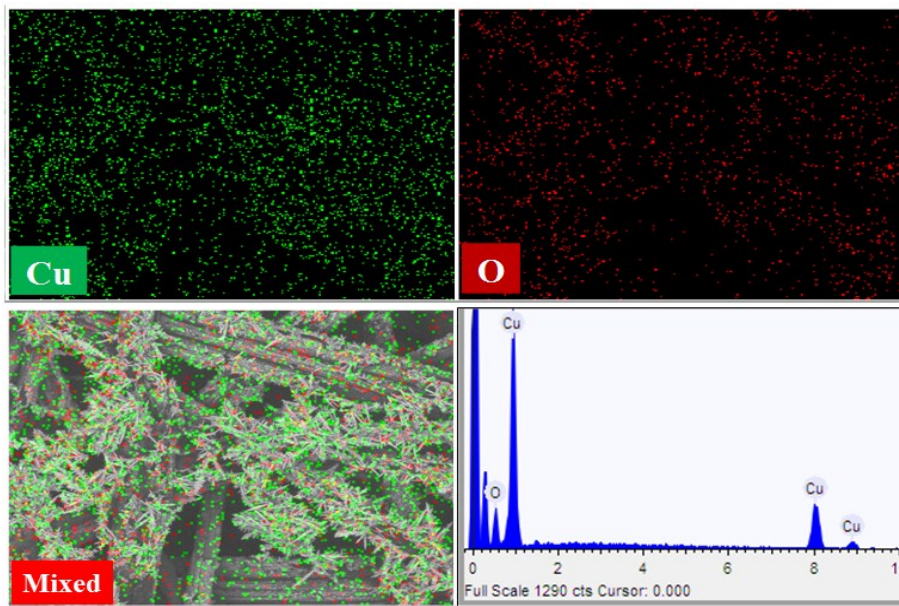
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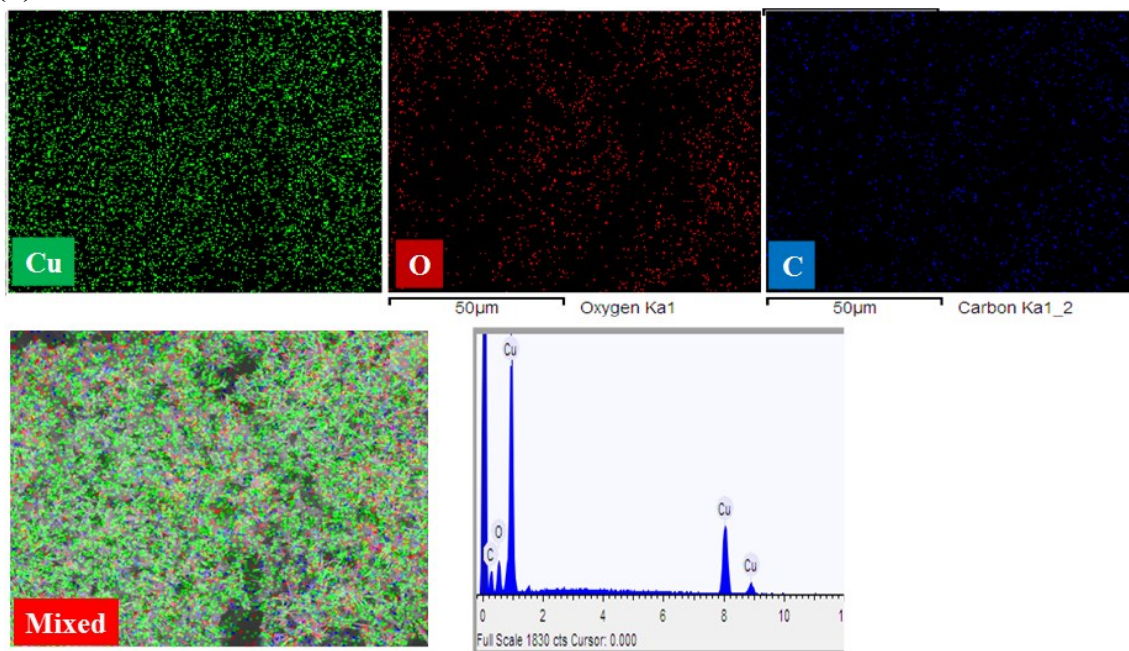
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83 (c) fCu/Cu<sub>x</sub>O



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85 (d) fCu/Cu<sub>x</sub>O-GO



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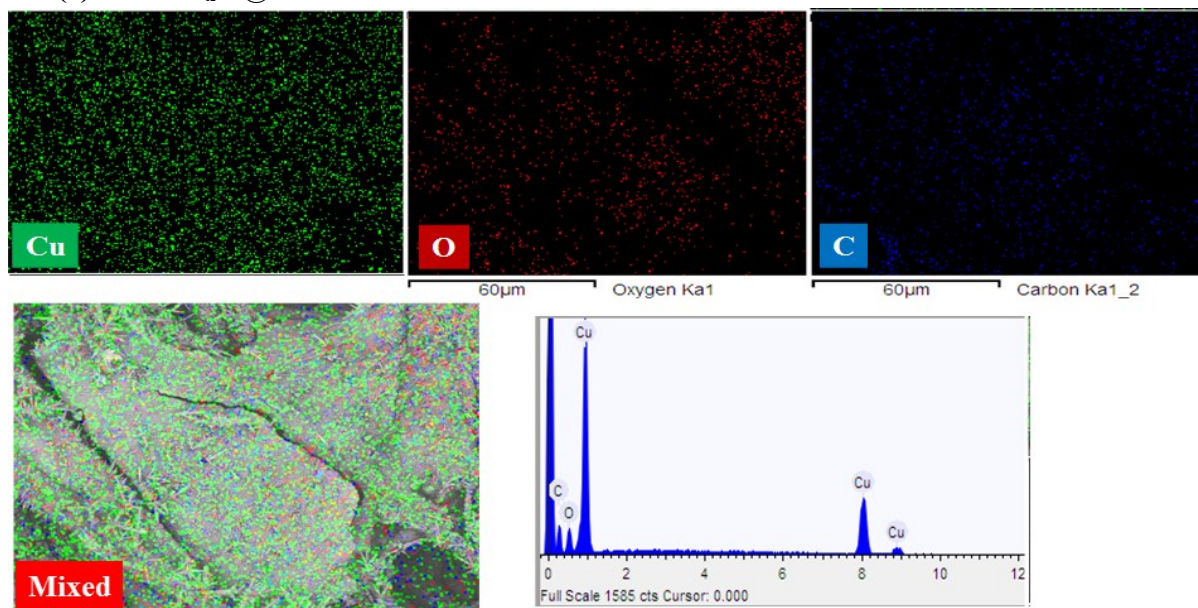
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94 (e) fCu/Cu<sub>x</sub>O@GO

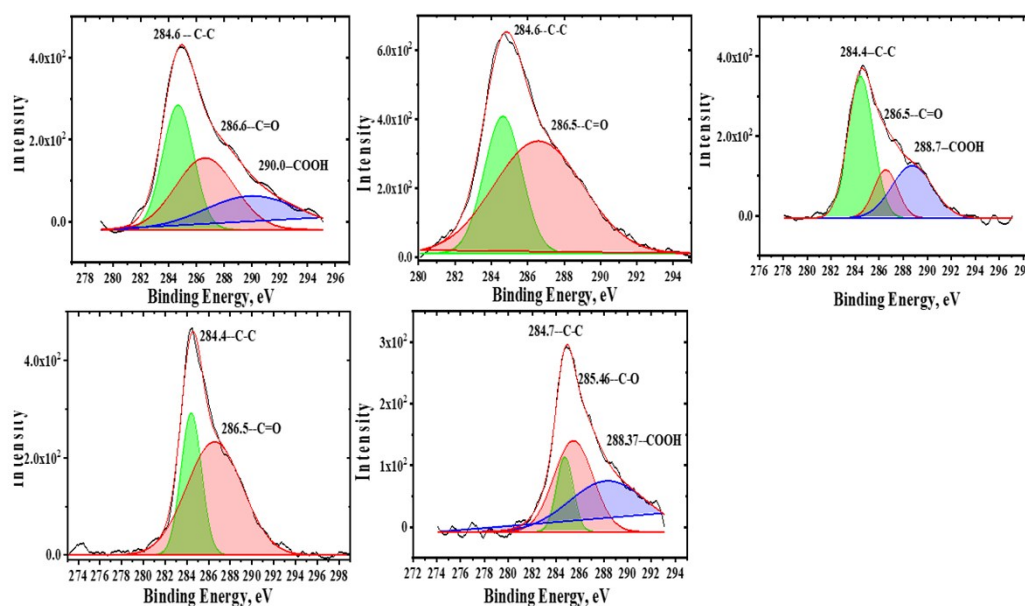


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96 *Figure SI-4: Detailed EDX elemental scans for the materials.*

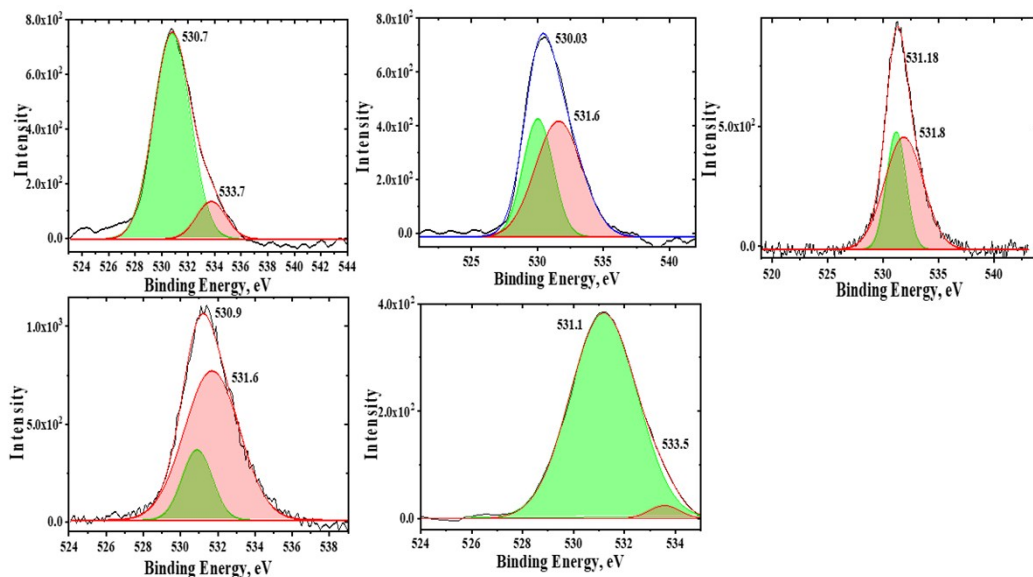
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100 *Figure SI-5: Detailed XPS scan for C 1s in the materials prepared, showing peaks for -C-C,*  
 101 *-C=O and -COOH groups. Materials without GO show presence of all three functional groups*  
 102 *while materials where GO was added show that -COOH group is no longer present suggesting*  
 103 *locking of the group by interacting with metal centre. (a) pCu/Cu<sub>x</sub>O, (b) pCu/Cu<sub>x</sub>O-GO, (c)*  
 104 *fCu/Cu<sub>x</sub>O, (d) fCu/Cu<sub>x</sub>O-GO, and (e) fCu/Cu<sub>x</sub>O@GO.*



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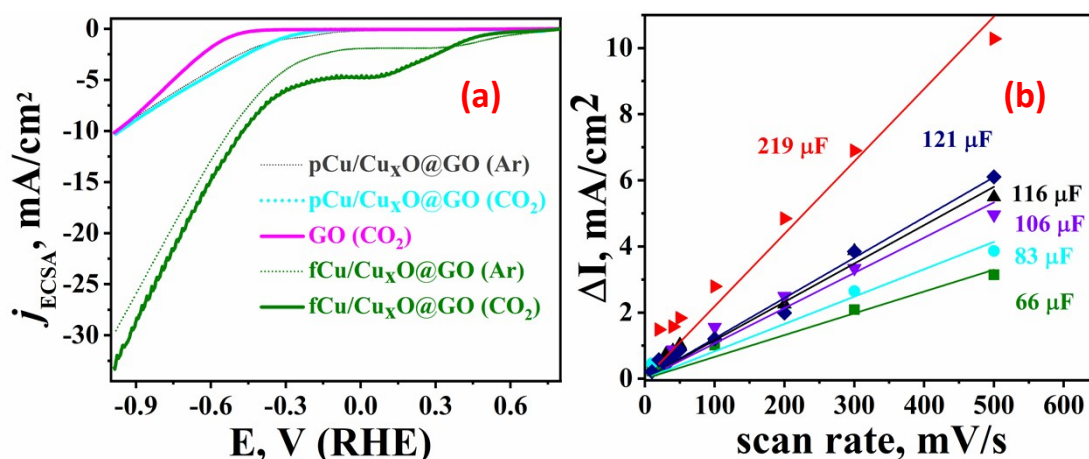
106 **Figure SI-6:** Detailed XPS scan for O 1s in all of the materials showing peaks for oxide phase  
 107 and -OH phase. (a) pCu/Cu<sub>x</sub>O, (b) pCu/Cu<sub>x</sub>O-GO, (c) fCu/Cu<sub>x</sub>O, (d) fCu/Cu<sub>x</sub>O-GO, and (e)  
 108 fCu/Cu<sub>x</sub>O@GO.

109

110 **Table SI-2:** XPS peak positions along with ratio of Cu<sup>2+</sup> to Cu<sup>+</sup>.

S.No.	Sample	Cu 2p	O 1s	C 1s	Cu <sup>2+</sup> /Cu <sup>+</sup> (area)
1	pCu/Cu <sub>x</sub> O	932.6	530.7	284.6	1.64
		933.8	533.7	286.6	
				290.0	
2	pCu/Cu <sub>x</sub> O-GO	932.5	530.0	284.6	3.99
		933.9	531.6	286.5	
3	fCu/Cu <sub>x</sub> O	931.8	531.1	284.4	1.56
		933.7	521.8	286.5	
				288.7	
4	fCu/Cu <sub>x</sub> O-GO	931.8	530.9	284.4	4.81
		933.5	531.6	286.5	
5	fCu/Cu <sub>x</sub> O@GO	932.8	531.1	284.7	1.25
		934.0	533.5	285.4	
				288.3	

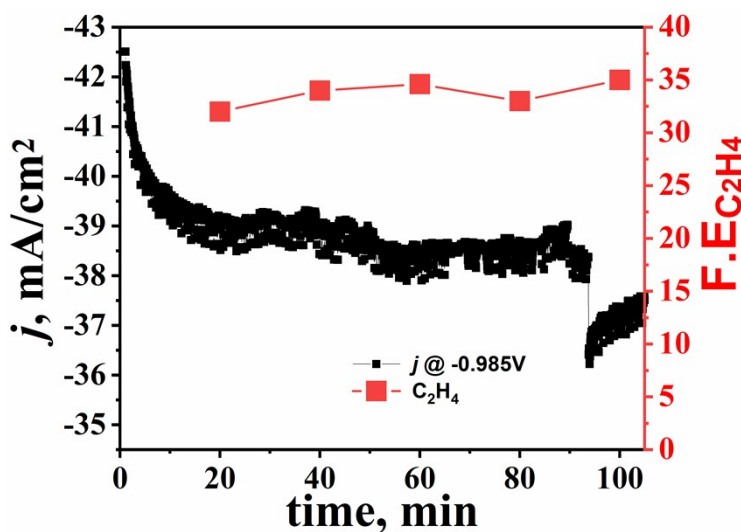
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113 **Figure SI-7:** (a) LSV traces of fCu/Cu<sub>x</sub>O@GO and pCu/Cu<sub>x</sub>O@GO and GO in 0.2 M KHCO<sub>3</sub>  
 114 saturated with CO<sub>2</sub>. (b) Current as a function of scan rate to calculate capacitance of the  
 115 materials,  $\blacktriangle$  pCu/Cu<sub>x</sub>O,  $\blacktriangleright$  pCu/Cu<sub>x</sub>O-GO,  $\blacktriangledown$  fCu/Cu<sub>x</sub>O,  $\blacklozenge$  fCu/Cu<sub>x</sub>O-GO,  $\bullet$  fCu/Cu<sub>x</sub>O@GO,  
 116  $\blacksquare$  pCu/Cu<sub>x</sub>O@GO.

117 The only detected liquid product was formic acid (NMR) at 8.4 ppm and its accumulative  
 118 concentration for one hour was highest recorded at fCu/Cu<sub>x</sub>O with 8%, and it was recorded at  
 119 3.9% with pCu/Cu<sub>x</sub>O-GO and not detected at electrodes modified with fCu/Cu<sub>x</sub>O@GO and  
 120 pCu/Cu<sub>x</sub>O@GO.



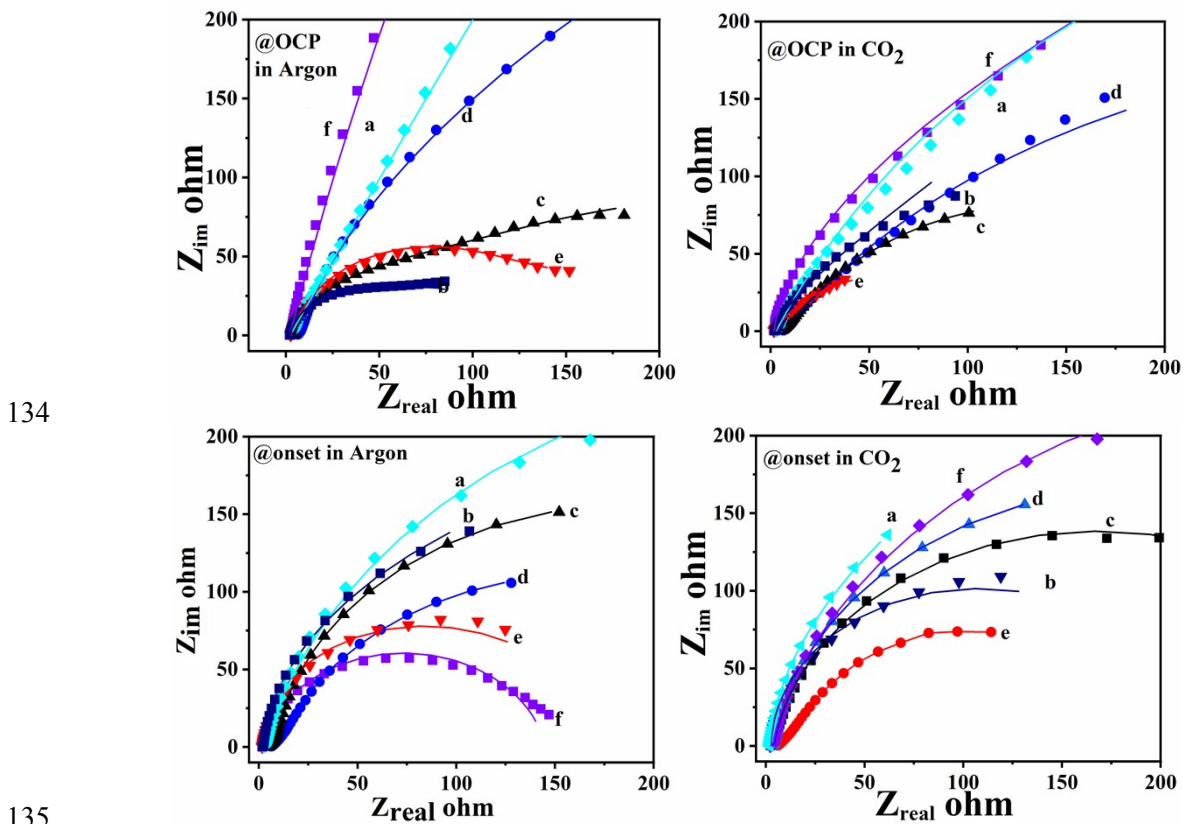
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122 **Figure SI-8:** The time-dependent current density and F.E. curves for the production of ethylene  
 123 on pCu/CuxO-GO at -0.98 V vs RHE over the time span of 100 minutes.

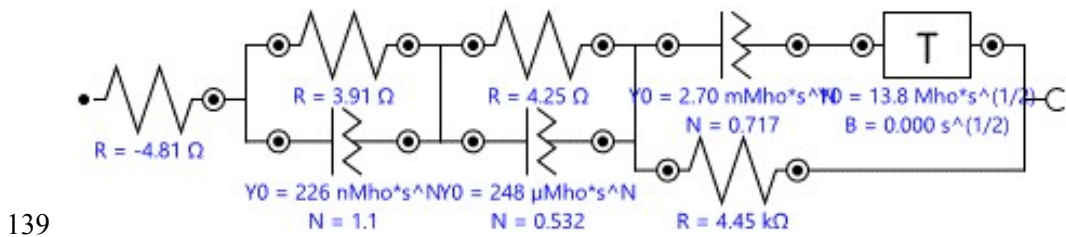
124 **Electrochemical Impedance analysis (EIS):** To probe the charge transfer dynamics, EIS  
 125 studies (SI-9) at different potentials and in presence and absence of CO<sub>2</sub> were recorded. The  
 126 equivalent circuits for the Nyquist plots are given in Figure SI-9. At open circuit potential in  
 127 presence of argon, charge transfer resistances are more than in presence of CO<sub>2</sub> suggesting that  
 128 reduction of CO<sub>2</sub> may be easy on these surfaces than HER, occurring in absence of CO<sub>2</sub>, and  
 129 pCu/Cu<sub>x</sub>O-GO composites show better electrochemical activity. At the onset potential, the  
 130 reaction starts and charge transfer resistances in argon saturated are lowered and suggesting



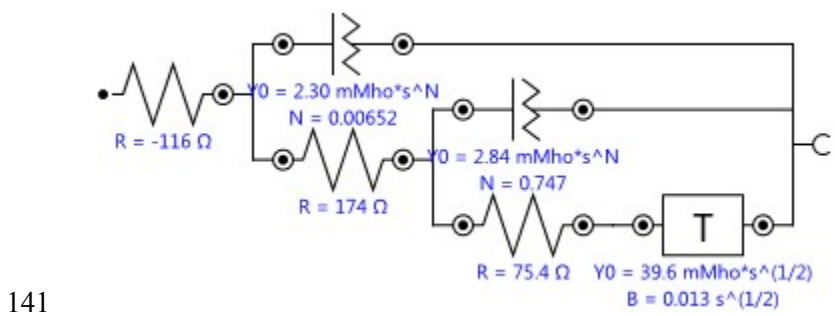
131 HER occurring at the surfaces. In presence of CO<sub>2</sub>, pCu/Cu<sub>x</sub>O-GO shows minimum resistance  
 132 hence should be efficient towards the ERC; also, pCu/Cu<sub>x</sub>O-GO is not very good for HER even  
 133 in absence of CO<sub>2</sub>.



136 **Figure SI-9:** Nyquist plots recorded in presence and absence of CO<sub>2</sub> at OCPs (upper panel),  
 137 and onset potentials (bottom panel). (a) fCu/Cu<sub>x</sub>O@GO, (b) fCu/Cu<sub>x</sub>O-GO, (c) pCu/Cu<sub>x</sub>O, (d)  
 138 fCu/Cu<sub>x</sub>O, (e) pCu/Cu<sub>x</sub>O-GO and (f) pCu/Cu<sub>x</sub>O@GO.



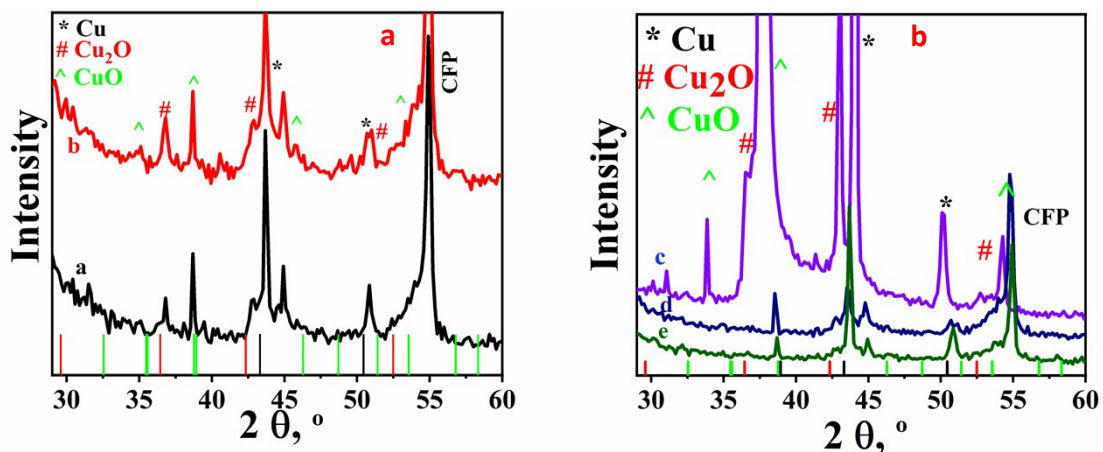
140 **Figure SI-10 (a):** Equivalent circuit in Argon saturated solution.



142 **Figure SI-10 (b):** Equivalent circuit in CO<sub>2</sub> saturated solution.

143 **Stability of catalysts:**

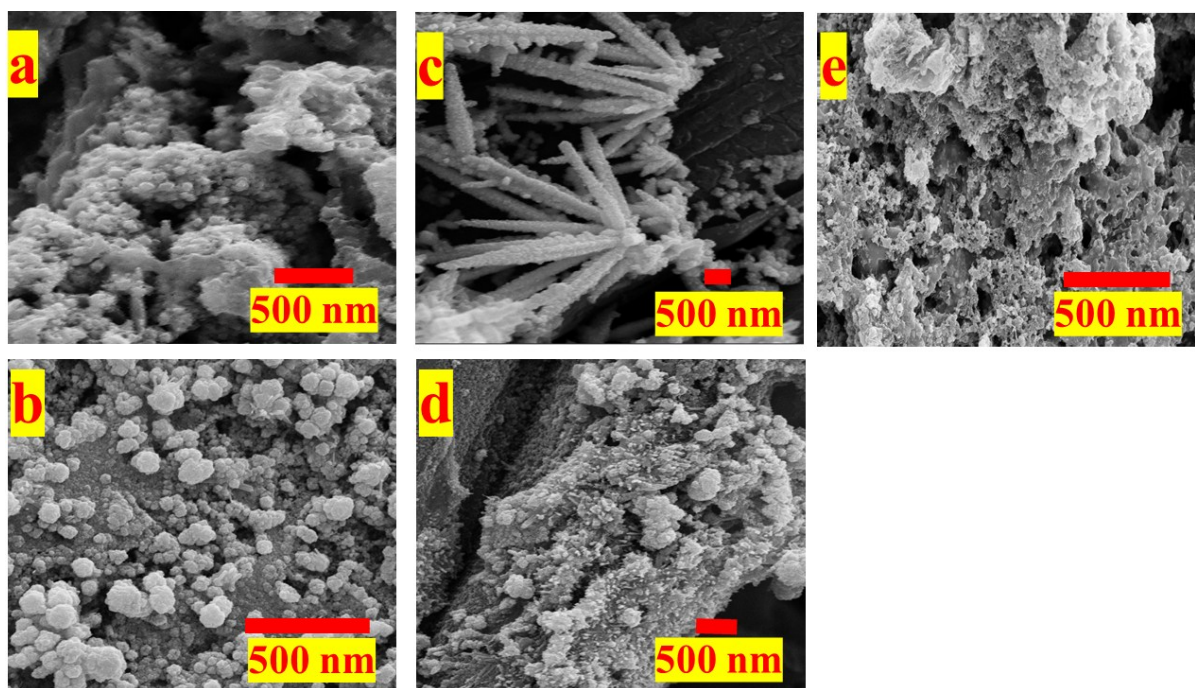
144 ERC at higher negative potentials is associated with reduction of the copper oxide and  
145 this reduction leads to the degradation of catalyst activity and breakdown of morphology. The  
146 nano-morphological stability of the materials after prolonged electrolysis was checked by  
147 analyzing the spent (used materials) with XRD and FSEM. Figure SI-10 shows the phase  
148 transformation of the catalysts after electrolysis of 7 hours at -0.985 V vs RHE. Peaks because  
149 of metallic copper are more intense than the copper oxide peaks which is due to the  
150 electrochemical reduction of  $Cu_xO$  during ERC. The morphology of the catalysts after bulk  
151 electrolysis was found to be intact as seen in FESEM images, SI-11, wherein pCu/ $Cu_xO$ ,  
152 conical structures are not ubiquitous. The pCu/ $Cu_xO$ -GO shows agglomeration of particles but  
153 looks similar to the unspent assembly of particles on GO. fCu/ $Cu_xO$  and fCu/ $Cu_xO$ -GO show  
154 no pronounced effect of prolonged electrolysis, while fCu/ $Cu_xO$ @GO shows agglomeration  
155 of the particles over GO sheets. This morphological stability even after 7 hours of continuous  
156 electrolysis highlights the stability and durability of these synthesized catalysts.



157

158 **Figure SI-11:** XRD graphs of the catalyst surfaces post-electrolysis at -0.985V, (left panel) (a  
159 trace) pCu/ $Cu_xO$ , (b trace) pCu/ $Cu_xO$ -GO, and (right panel) (c trace) fCu/ $Cu_xO$ , (d trace)  
160 fCu/ $Cu_xO$ -GO, (e trace) fCu/ $Cu_xO$ @GO.

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162

163 **Figure SI-12:** morphological transformation of the spent materials. The images show that the  
 164 prolonged electrolysis does not affect the morphology of composites and hence the catalysts  
 165 are stable for longer run times for ERC, (a) pCu/Cu<sub>x</sub>O, (b) pCu/Cu<sub>x</sub>O-GO, (c) fCu/Cu<sub>x</sub>O, (d)  
 166 pCu/Cu<sub>x</sub>O-GO and (e) fCu/Cu<sub>x</sub>O@GO.

167 **References:**

- 168 1. R. Saito, M. Hofmann, G. Dresselhaus, A. Jorio, M. S. Dresselhaus, *Advances in Physics*, 2011,  
 169 **60.**